**Wafer Report**

**Processed Image**

**General**
- Measured: 27/06/2014 11:09 AM
- Operator: Jason
- Sample ID: 6823
- Batch: Multi Demo Batch

**Results**
- Mean PL: 490
- Lifetime: 1.430
- Thickness: 180.617
- Resistivity: 1.473

**Analysis**
- Recipe: multi default
- Bin: 1
- Grade: A1
- Q: 0.626

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<tr>
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<tbody>
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**Wafer Report**

**Processed Image**

**General**
- Measured: 27/06/2014 10:33 AM
- Operator: Jason
- Sample ID: 8525
- Batch: Multi Demo Batch

**Results**
- Mean PL: 667
- Lifetime: 1.437
- Thickness: 185.081
- Resistivity: 1.413

**Analysis**
- Recipe: multi default
- Bin: 2
- Grade: B1
- Q: 0.875

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